## **MUR1620CT**

# GLASS PASSIVATED HIGH EFFICENCY RECTIFIER Reverse Voltage – 50 to 1000 Volts

Forward Current – 16.0 Amperes

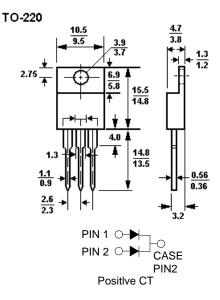
#### **Features**

- · Low forward voltage, High current capability
- Plastic package has Underwriters Laboratory Flammability Classification 94V-O utilizing Flame Retardant Epoxy Molding Compound.
- High surge capacity
- Low power loss, high efficiency
- Ultra fast recovery times, high voltage

#### **Mechanical Data**

 Case: Molded plastic, TO-220
Terminals: leads solderable per MIL-STD-202, method 208 guaranteed

Polarity: As markedMounting Position: Any



## **Absolute Maximum Ratings and Characteristics**

### **Dimensions in mm**

Ratings at 25°C ambient temperature unless otherwise specified. Single phase, half wave,60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

	Symbols	Value	Units
Maximum recurrent peak reverse voltage	$V_{RRM}$	200	Volts
Maximum RMS voltage	V <sub>RMS</sub>	140	Volts
Maximum DC blocking voltage	V <sub>DC</sub>	200	Volts
Maximum average forward Rectified curren	t		
at T <sub>C</sub> = 100 ℃	I <sub>F(AV)</sub>	16.0	Amps
Peak forward surge current			
8.3ms single half-sine-wave superimposed	I <sub>FSM</sub>	125	Amps
on rated load (JEDEC method)			
Maximum forward voltage at 8.0A and T <sub>A</sub> =	25℃ V <sub>F</sub>	1.0	Volts
Typical junction Capacitance (Note1)	C <sub>J</sub>	80	pF
Maximum reverse recovery time (Note 2)	T <sub>RR</sub>	50	nS
Typical thermal resistance (Note3)	R <sub>0JC</sub>	3.0	°C/W
Maximum reverse current at @T <sub>A</sub> =	25℃	10	μAmps
rated DC blocking voltage @T <sub>C</sub> =	125℃ I <sub>R</sub>	500	μAmps
Operating and storage temperature range	$T_J$ , $T_{Stg}$	-55 to +150	$^{\circ}\mathbb{C}$

Notes: 1. Measured at 1 MHz and applied reverse voltage of 4.0 VDC.

- 2. Reverse recovery test conditions:  $I_F = 0.5A$ ,  $I_R = 1A$ ,  $I_{RR} = 0.25A$
- 3. Thermal resistance from junction to case per leg mounted on heatsink.



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FIG.1 Reverse Recovery Time Characteristic and Test Circuit Diagram

